Tuesday October 28, 2014

08.45 - 09.00	Registration: outside Kollektorn
09.00 - 12.15	LECTURE HALL Kollektorn
09.00 - 09.20	Welcome address and introductory remarks by the organizers Lena Falk and Mats Halvarsson, Applied Physics, Chalmers
09.20 - 10.00	Introduction to modern technologies in scanning electron microscopy Mats Eriksson, Spectral Solutions, Sweden
10.00 - 10.30	COFFEE in the Canyon
10.30 - 11.10	Advancing feature analysis and spectrum imaging: Introduction to analytical tools, setting up measurement conditions, improving the spatial resolution Tobias Salge, Bruker Nano GmbH, Germany
11.10 - 11.20	BREAK
11.20 - 12.00	Focused ion beam / scanning electron microscope instruments Ingo Schulmeyer, Carl Zeiss NTS GmbH, Germany
12.00 - 13.00	LUNCH in the Canyon
13.00 - 19.00	PRACTICALS
13.00 - 14.15	Demonstrations Session I
14.15 - 14.45	COFFEE in the Canyon
14.45 - 17.15	Demonstrations Session II
17.15 - 19.00	Open Lab

COURSE DINNER in the Canyon

19.00

Wednesday October 29, 2014

09.00 - 12.00	LECTURE HALL KOLLEKTORN
09.00 - 09.05	Introductory remarks by the organizers
09.05 - 09.45	Challenging particle analysis Matthew Hiscock, Oxford Instruments NanoAnalysis, UK
09.45 - 10.15	COFFEE in the Canyon
10.15 - 10.45	High resolution imaging at low kV Patrick Woo, Hitachi High-Technologies Canada, Inc., Canada
10.45 - 11.15	Preparing near perfect sample surfaces for near perfect SEM's Håkan Vikström, Oxford Instruments Nordiska AB, Sweden
11.15 - 11.20	BREAK
11.20 - 12.00	Solutions for correlative electron microscopy and analysis Sonja Gürster, Jeol (Germany) GmbH
12.00 - 13.00	LUNCH in the Canyon
13.00 - 20.00	PRACTICALS
13.00 - 14.15	Demonstrations Session III
14.15 - 14.45	COFFEE in the Canyon
14.45 - 17.15	Demonstrations Session IV
17.15	SANDWICHES and REFRESHMENTS
17.15 - 20.00	Open Lab

Thursday October 30, 2014

09.00 - 12.00	LECTURE HALL KOLLEKTORN
09.00 - 09.05	Introductory remarks by the organizers
09.05 - 09.45	Visualize - analyze - understand: Materials Science in 3D Peter Westenberger, FEI Company, The Netherlands
09.45 - 10.15	COFFEE in the CANYON
10.15 - 10.45	Macro-, to micro-, to nanoscale analysis using advancing feature analysis and apectrum imaging: applications in nano, material, life earth and planetary sciences Tobias Salge, Bruker Nano GmbH, Berlin, Germany
10.45 - 11.15	Image analysis with a desktop SEM Jeroen Smulders, Phenom-World BV., The Netherlands
11.15 - 11.50	Panel discussion
11.50 - 12.00	Concluding remarks by the organizers
12.00 - 13.00	LUNCH in the CANYON
13.00 - 15.45	PRACTICALS
13.00 - 14.15	Demonstrations Session V
14.15 - 14.30	COFFEE in the CANYON
14.30 - 15.45	Demonstrations Session VI
15.45	End of Course